

Notice of References CitedApplication/Control No.
09/923,604Applicant(s)/Patent Under
Reexamination
HAPKE, FRIEDRICHExaminer
John P TrimmingsArt Unit
2133

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,366,393	12-1982	Kasuya, Yoshihiro	326/16
	B	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Compact Two-Pattern Test Set Generation for Combinational and Full Scan Circuits", Hamzaoglu et al., Test Conference Proceedings, 18-23 October 1998, pp 944-953.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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